

# Search Notes



Application/Control No.

09/873,815

Examiner

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Applicant(s)/Patent under Reexamination

LAVORGNA ET AL.

Art Unit

3629

## SEARCHED

Class	Subclass	Date	Examiner
705	7	2/06	DN
	8		
	10		
715	513		
707	100		
345	260		
382	180		
715	514		
	515		
707	200	✓	✓

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
	3/06	
I US	2/06	DN
Patent		
PG Pub		
II FOREIGN		
1. EPO		
2. JPO		
3. Derwent		
IBM TOB		
	✓	✓